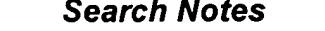


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/019,332	SHINO ET AL.
	Examiner	Art Unit
	Danny Wai Lun Leung	2633

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
398	41	1/24/2006	DWL
398	138-139	1/24/2006	DWL